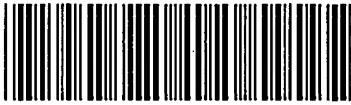


Search Notes

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Examiner

Khanh V. Nguyen

Applicant(s)/Patent under
Reexamination

CHEN, YEN-CHUNG T.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See Search History Printout		9/14/2005	NKV

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	9/14/2005	NKV